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September 16th, 2013

Dear Valued Bruker AFM Probes Customer,

Bruker is pleased to announce the introduction of our new range of Silicon TESP/TESPA probes.

Models TESP & TESPA will be replaced by TESP-V2 TESPW-V2 & TESPA-V2, TESPAW-V2. The probes are very similar in design with improvements in quality and tightening of dimensional variation. A summary comparison chart is attached for your reference. Full specification details can be found on www.brukerAFMprobes.com

Bruker is providing advanced notice to you to ensure a sufficient time for transition to these new probes. It is anticipated that sales of the current probe models will be available until the end of March 2014. When you come to re-order TESP/A probes, please order the new probes.

Bruker appreciates your business and continuing confidence in our products and technology. We will continue to support your investment in Bruker AFM's in the years to come.

Please consult your local Bruker representative for any questions regarding this policy or email us at probesinfo@bruker-nano.com or at one of the regional contact emails below.

Lastly please take time to visit our website, www.brukerAFMprobes.com for the latest information, promotions and announcement concerning AFM probes.

Your Bruker AFM Probes Team
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Attachment

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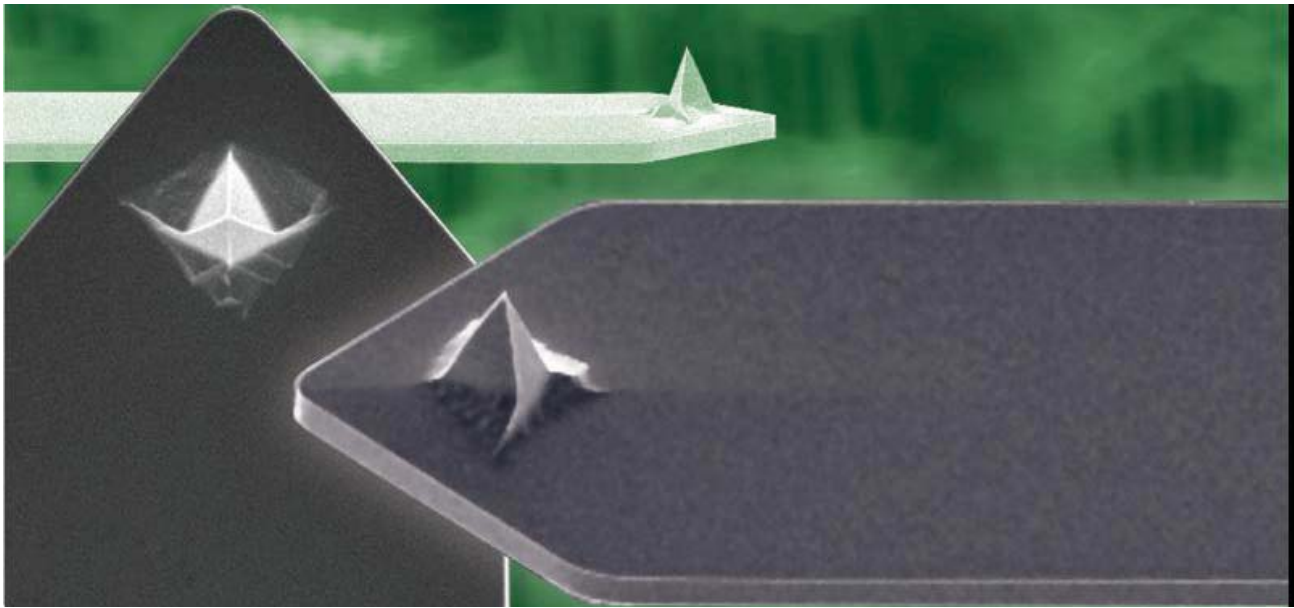
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Summary Comparison Tables & Probe Images



Model Comparison

Legacy TESP/TESPA Specifications

Model #	Description			
TESP	Pack of 10 unmounted probes; TappingMode & non-contact modes			
TESP-W	One wafer of unmounted probes; TappingMode & non-contact modes			
TESPA	Pack of 10 unmounted probes; TappingMode & non-contact modes; Al backside cantilever coating			
TESPA-W	One wafer of unmounted probes; TappingMode & non-contact modes; Al backside cantilever coating			
	Units	Nom	Min	Max
Eff. Lever Length	μm	125	110	140
Lever Width	μm	40	30	50
Lever Thickness	μm	4	3.25	4.75
Tip Height	μm	12.5	10	15
Tip Setback	μm	15	5	25
Frequency	kHz	320	230	410
Stiffness	N/m	42	20	80
Estimated Tip Radius	nm	8	-	12.5

New TESP-V2/TESPA-V2 Specifications

Model #	Description			
TESP-V2	Pack of 10 unmounted probes; TappingMode & non-contact modes			
TESPW-V2	One wafer of unmounted probes; TappingMode & non-contact modes			
TESPA-V2	Pack of 10 unmounted probes; TappingMode & non-contact modes; Al backside cantilever coating			
TESPAW-V2	One wafer of unmounted probes; TappingMode & non-contact modes; Al backside cantilever coating			
	Units	Nom	Min	Max
Eff. Lever Length	μm	127	120	135
Lever Width	μm	35	34	36
Lever Thickness	μm	3.8	2.9	4.4
Tip Height	μm	12.5	10	15
Tip Setback	μm	13.5	11	16
Frequency	kHz	320	230	410
Stiffness	N/m	42	20	80
Estimated Tip Radius	nm	8	—	12.5